

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10652003	SESEK ET AL.
	Examiner	Art Unit
	Chawan, Sheela C	2624

SEARCHED

Class	Subclass	Date	Examiner
382	229, 172, 168, 275, 176, 163, 169, 270, 173	2/3/07	SCC
358	1.9, 2.99, 1.15, 465, 463, 462, 448, 464, 466, 453, 400, 402, 403, 3.22	"	"
434	362	"	"
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382/229, 168, 275, 254, 173, 176, 172, 163, 169, 270. CCLS.	"	"
358/ 1.15, 462, 453, 400, 403, 402, 1.9. CCLS, US- PATENT ONLY SEE TEXT SEARCH.	"	"
INTERFERENCE SEARCH , SEE SEARCH HISTORY PRINT OUT.	"	"
INVENTOR NAME SEARCH.	"	"
IEEE OR INSPEC DATA BASE.	"	"

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
382	229	2/3/07	SCC
358	1.9, 400, 453, 462	"	"